

Sample &

Buy



### CDCLVP1212

SCAS886D - AUGUST 2009 - REVISED SEPTEMBER 2014

# CDCLVP1212 LVPECL Output, High-Performance Clock Buffer

Technical

Documents

### 1 Features

- 2:12 Differential Buffer
- Selectable Clock Inputs Through Control Terminal
- Universal Inputs Accept LVPECL, LVDS, and LVCMOS/LVTTL
- 12 LVPECL Outputs
- Maximum Clock Frequency: 2 GHz
- Maximum Core Current Consumption: 88 mA
- Very Low Additive Jitter: <100 fs, rms in 10 kHz to 20-MHz Offset Range:
  - 57 fs, rms (typ) @ 122.88 MHz
  - 48 fs, rms (typ) @ 156.25 MHz
  - 30 fs, rms (typ) @ 312.5 MHz
- 2.375 V to 3.6 V Device Power Supply
- Maximum Propagation Delay: 550 ps
- Maximum Output Skew: 25 ps
- LVPECL Reference Voltage, V<sub>AC\_REF</sub>, Available for Capacitive-Coupled Inputs
- Industrial Temperature Range: -40°C to +85°C
- ESD Protection Exceeds 2 kV (HBM)
- Available in 6mm × 6mm QFN-40 (RHA) Package

# 2 Applications

- Wireless Communications
- Telecommunications/Networking
- Medical Imaging
- Test and Measurement Equipment

# 3 Description

Tools &

Software

The CDCLVP1212 is a highly versatile, low additive jitter buffer that can generate 12 copies of LVPECL clock outputs from one of two selectable LVPECL, LVDS, or LVCMOS inputs for a variety of communication applications. It has a maximum clock frequency up to 2 GHz. The CDCLVP1212 features an on-chip multiplexer (MUX) for selecting one of two inputs that can be easily configured solely through a terminal. The overall additive jitter control performance is less than 0.1 ps, RMS from 10 kHz to 20 MHz, and overall output skew is as low as 25 ps, making the device a perfect choice for use in demanding applications.

Support &

Community

**.**...

The CDCLVP1212 clock buffer distributes one of two selectable clock inputs (IN0, IN1) to 12 pairs of differential LVPECL clock outputs (OUT0, OUT11) with minimum skew for clock distribution. The CDCLVP1212 can accept two clock sources into an input multiplexer. The inputs can be LVPECL, LVDS, or LVCMOS/LVTTL.

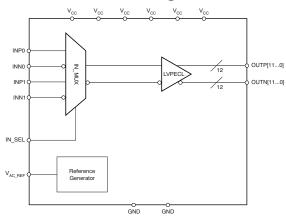
The CDCLVP1212 is specifically designed for driving 50- $\Omega$  transmission lines. When driving the inputs in single-ended mode, the LVPECL bias voltage (V<sub>AC\_REF</sub>) should be applied to the unused negative input terminal. However, for high-speed performance up to 2 GHz, differential mode is strongly recommended.

The CDCLVP1212 is packaged in a small 40terminal, 6 mm x 6 mm QFN package and is characterized for operation from  $-40^{\circ}$ C to  $+85^{\circ}$ C.

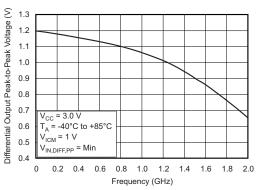
Device Information				
PART NUMBER	PACKAGE	BODY SIZE (NOM)		
CDCLVP1212	QFN (40)	6.00 mm x 6.00 mm		

(1) For all available packages, see the orderable addendum at the end of the datasheet.

# 4 Functional Block Diagram



### Peak-to-Peak Voltage vs. Frequency



An IMPORTANT NOTICE at the end of this data sheet addresses availability, warranty, changes, use in safety-critical applications, intellectual property matters and other important disclaimers. PRODUCTION DATA.

Copyright © 2009–2014, Texas Instruments Incorporated

# **Table of Contents**

1	Feat	ures	1
2	Арр	lications	1
3	Des	cription	1
4	Fun	ctional Block Diagram	1
5	Rev	ision History	2
6	Dev	ice Comparison Table	4
7		Configuration and Functions	
8	Spe	cifications	6
	8.1	Pin Characteristics	6
	8.2	Absolute Maximum Ratings	6
	8.3	Handling Ratings	6
	8.4	Recommended Operating Conditions	6
	8.5	Thermal Information	6
	8.6	Electrical Characteristics: LVCMOS Input	7
	8.7	Electrical Characteristics: Differential Input	
	8.8	Electrical Characteristics: LVPECL Output, At V_{CC} = 2.375 V to 2.625 V	
	8.9	Electrical Characteristics: LVPECL Output, at V_{CC} = 3.0 V to 3.6 V	9
	8.10	Timing Requirements 1	0
	8.11	Typical Characteristics 1	1
9	Para	ameter Measurement Information 1	2

	9.1	Test Configurations	12
10	Deta	iled Description	14
	10.1		
	10.2	Functional Block Diagram	14
	10.3	Feature Description	14
	10.4	Device Functional Modes	14
11	Appl	ications and Implementation	19
	11.1	Application Information	
	11.2	Typical Application	19
12		er Supply Recommendations	
		Thermal Management	
13		out	
		Layout Guidelines	
		Layout Example	
14		ce and Documentation Support	
	14.1		
	14.2	Trademarks	
	14.3	Electrostatic Discharge Caution	23
	14.4	-	
15	Mecl	hanical, Packaging, and Orderable	
		mation	23

# 5 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

C	nanges from Revision C (June 2014) to Revision D	Page
•	Added "NOTE" at the beginning of "Applications and Implementation" section	19
•	Changed JEDEC symbol to R <sub>0JA</sub>	22
C	nanges from Revision B (Augsut 2011) to Revision C	Page
•	Changed data sheet flow and layout to conform with new TI standards. Added the following sections: Application and Implementation; Power Supply Recommendations; Layout; Device and Documentation Support; Mechanical, Packaging, and Ordering Information	1
•	Added f <sub>IN</sub> = 125 MHz, 312.5 MHz for V <sub>OUT, DIFF, PP</sub>	7
•	Added Typical values, Max values, and footnotes for 122.88 MHz, 156.25 MHz, and 312.5 MHz test conditions corresponding to Random Additive Jitter in Electrical Characteristics: LVPECL Output, At $V_{CC}$ = 2.375 V to 2.625 V.	8
•	Added Typical values, Max values, and footnotes for 122.88 MHz, 156.25 MHz, and 312.5 MHz test conditions corresponding to Random Additive Jitter in Electrical Characteristics: LVPECL Output, at $V_{CC}$ = 3.0 V to 3.6 V	9
CI	nanges from Revision A (May, 2010) to Revision B	Page
•	Revised description of pin 7	5
•	Corrected VIL parameter description in <i>Electrical Characteristics</i> table for LVCMOS inputs	7
•	Added footnote (2) to <i>Electrical Characteristics</i> table for LVPECL Output, V <sub>CC</sub> = 2.375 V to 2.625 V	7
•	Added footnote (2) to <i>Electrical Characteristics</i> table for LVPECL Output, V <sub>CC</sub> = 2.375 V to 2.625 V	<mark>8</mark>





CI	hanges from Original (August, 2009) to Revision A	Page
•	Corrected package designators in orderable device names in the Device Comparison Table	4
•	Changed description of INP1, INP0 and INN1, INN0 pins in <i>Pin Descriptions</i> table	4
•	Changed descriptions of all output pins in <i>Pin Descriptions</i> table	4

ISTRUMENTS

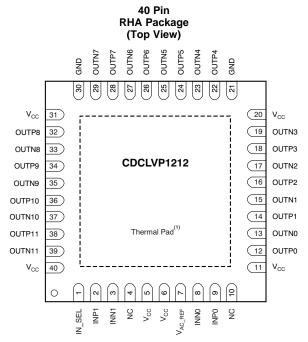
EXAS

# 6 Device Comparison Table<sup>(1)</sup>

PACKAGED DEVICES T <sub>A</sub>		FEATURES
CDCLVP1212RHAT	-40°C to +85°C	40 terminal QFN (RHA) package, small tape and reel
CDCLVP1212RHAR	–40°C to +85°C	40 terminal QFN (RHA) package, tape and reel

(1) For the most current specifications and package information, see the Package Option Addendum located at the end of this data sheet or refer to our web site at www.ti.com.

# 7 Pin Configuration and Functions



(1) Thermal pad must be soldered to ground.

### **Pin Functions**

PIN			PULL-UP/		
NAME	NUMBER	TYPE	PULLDOWN	DESCRIPTION	
V <sub>CC</sub>	5, 6, 11, 20, 31, 40	Power	_	2.5 V/3.3 V supplies for the device	
GND	21, 30	Ground	—	Device grounds	
INP0, INN0	9, 8	Input	—	Differential input pair or single-ended input. Unused input pair can be left floating.	
INP1, INN1	2, 3	Input	_	Redundant differential input pair or single-ended input. Unused input pair can be left floating.	
OUTP11, OUTN11	38, 39	Output	_	Differential LVPECL output pair no. 11. Unused output pair can be left floating.	
OUTP10, OUTN10	36, 37	Output	_	Differential LVPECL output pair no. 10. Unused output pair can be left floating.	
OUTP9, OUTN9	34, 35	Output	_	Differential LVPECL output pair no. 9. Unused output pair can be left floating.	
OUTP8, OUTN8	32, 33	Output	_	Differential LVPECL output pair no. 8. Unused output pair can be left floating.	
OUTP7, OUTN7	28, 29	Output	_	Differential LVPECL output pair no. 7. Unused output pair can be left floating.	



CDCLVP1212 SCAS886D – AUGUST 2009 – REVISED SEPTEMBER 2014

#### www.ti.com

# Pin Functions (continued)

PIN						
NAME	NUMBER	TYPE	PULL-UP/ PULLDOWN	DESCRIPTION		
OUTP6, OUTN6	26, 27	Output	_	Differential LVPECL output pair no. 6. Unused output pair can be left floating.		
OUTP5, OUTN5	24, 25	Output	_	Differential LVPECL output pair no. 5. Unused output pair can be left floating.		
OUTP4, OUTN4	22, 23	Output	_	Differential LVPECL output pair no. 4. Unused output pair can be left floating.		
OUTP3, OUTN3	18, 19	Output	_	Differential LVPECL output pair no. 3. Unused output pair can be left floating.		
OUTP2, OUTN2	16, 17	Output	_	Differential LVPECL output pair no. 2. Unused output pair can be left floating.		
OUTP1, OUTN1	14, 15	Output	_	Differential LVPECL output pair no. 1. Unused output pair can be left floating.		
OUTP0 OUTN0	12, 13	Output	_	Differential LVPECL output pair no. 0. Unused output pair can be left floating.		
IN_SEL	1	Input	Pulldown (see Pin Characteristics)	MUX select input for input choice (see Table 1)		
V <sub>AC_REF</sub>	7	Output	_	Bias voltage output for capacitive coupled inputs. Do not use $V_{AC\_REF}$ at $V_{CC} < 3.0 \text{ V}$ . If used, it is recommended to use a 0.1-µF capacitor to GND on this terminal. The output current is limited to 2 mA.		
NC	4, 10	—	—	Do not connect		

# Table 1. Input Selection Table

IN_SEL	ACTIVE CLOCK INPUT
0	INP0, INN0
1	INP1, INN1

TEXAS INSTRUMENTS

www.ti.com

## 8 Specifications

### 8.1 Pin Characteristics

PARAMETER		MIN	TYP	MAX	UNIT
R <sub>PULLDOWN</sub>	Input pulldown resistor		150		kΩ

## 8.2 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) <sup>(1)</sup>

		MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range <sup>(2)</sup>	-0.5	4.6	V
V <sub>IN</sub>	Input voltage range <sup>(3)</sup>	-0.5	V <sub>CC</sub> + 0.5	V
V <sub>OUT</sub>	Output voltage range <sup>(3)</sup>	-0.5	V <sub>CC</sub> + 0.5	V
I <sub>IN</sub>	Input current		20	mA
I <sub>OUT</sub>	Output current		50	mA
T <sub>A</sub>	Specified free-air temperature range (no airflow)	-40	+85	°C

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All supply voltages must be supplied simultaneously.

(3) The input and output negative voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

# 8.3 Handling Ratings

			MIN	MAX	UNIT
T <sub>stg</sub>	Storage temperature range		-65	+150	°C
TJ	Maximum junction temperatur	Maximum junction temperature			°C
V <sub>(ESD)</sub> <sup>(1)</sup>	Electrostatic Discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins <sup>(2)</sup>		2	kV

(1) Electrostatic discharge (ESD) to measure device sensitivity and immunity to damage caused by assembly line electrostatic discharges in to the device.

(2) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

# 8.4 Recommended Operating Conditions

Over operating free-air temperature range (unless otherwise noted).

		MIN	TYP	MAX	UNIT
V <sub>CC</sub>	Supply voltage	2.375	2.50/3.30	3.60	V
T <sub>A</sub>	Ambient temperature	-40		+85	°C

## 8.5 Thermal Information<sup>(1)(2)(3)</sup>

	THERMAL METRIC	VALUE	UNIT	
		36.1, 0 LFM <sup>(4)</sup>		
$R_{\theta JA}$	Thermal resistance, junction-to-ambient	30.2, 150 LFM <sup>(4)</sup>	0000	
		28.2, 400 LFM <sup>(4)</sup>	°C/W	
$\theta_{JP}^{(5)}$	Thermal resistance, junction-to-pad	3.58 <sup>(4)</sup>		

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

(2) The package thermal resistance is calculated in accordance with JESD 51 and JEDEC 2S2P (high-K board).

(3) Connected to GND with 16 thermal vias (0.3 mm diameter).

(4) 4 x 4 vias on Pad

(5) θ<sub>JP</sub> (junction-to-pad) is used for the QFN package, because the primary heat flow is from the junction to the GND pad of the QFN package.



# 8.6 Electrical Characteristics: LVCMOS Input <sup>(1)</sup>

At  $V_{CC}$  = 2.375 V to 3.6 V and  $T_A$  = -40°C to +85°C (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f <sub>IN</sub>	Input frequency				200	MHz
V <sub>th</sub>	Input threshold voltage	External threshold voltage applied to complementary input	1.1		1.8	V
V <sub>IH</sub>	Input high voltage		V <sub>th</sub> + 0.1		V <sub>CC</sub>	V
V <sub>IL</sub>	Input low voltage		0		$V_{th} - 0.1$	V
I <sub>IH</sub>	Input high current	V <sub>CC</sub> = 3.6 V, V <sub>IH</sub> = 3.6 V			40	μA
IIL	Input low current	V <sub>CC</sub> = 3.6 V, V <sub>IL</sub> = 0 V			-40	μA
$\Delta V / \Delta T$	Input edge rate	20% to 80%	1.5			V/ns
I <sub>CAP</sub>	Input capacitance			5		pF

(1) Figure 6 and Figure 7 show dc test setup.

## 8.7 Electrical Characteristics: Differential Input <sup>(1)</sup>

At V<sub>CC</sub> = 2.375 V to 3.6 V and T<sub>A</sub> =  $-40^{\circ}$ C to  $+85^{\circ}$ C (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
f <sub>IN</sub>	Input frequency	Clock input		2000	MHz
V	Differential input peak peak voltage	f <sub>IN</sub> ≤ 1.5 GHz	0.1	1.5	V
V <sub>IN, DIFF, PP</sub>	Differential input peak-peak voltage	$1.5 \text{ GHz} \le f_{\text{IN}} \le 2 \text{ GHz}$	0.2	1.5	V
VICM	Input common-mode level		1.0	$V_{CC} - 0.3$	V
I <sub>IH</sub>	Input high current	$V_{CC} = 3.6 \text{ V}, \text{ V}_{IH} = 3.6 \text{ V}$		40	μA
I <sub>IL</sub>	Input low current	$V_{CC}$ = 3.6 V, $V_{IL}$ = 0 V		-40	μA
ΔV/ΔΤ	Input edge rate	20% to 80%	1.5		V/ns
I <sub>CAP</sub>	Input capacitance			5	pF

(1) Figure 5 and Figure 8 show dc test setup. Figure 9 shows ac test setup.

# 8.8 Electrical Characteristics: LVPECL Output, At $V_{cc}$ = 2.375 V to 2.625 V<sup>(1)</sup>

 $T_A = -40^{\circ}C$  to +85°C (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
V <sub>OH</sub>	Output high voltage		V <sub>CC</sub> – 1.26	V <sub>CC</sub> – 0.9	V
V <sub>OL</sub>	Output low voltage		V <sub>CC</sub> – 1.7	V <sub>CC</sub> – 1.3	V
V <sub>OUT,</sub> diff, pp	Differential output peak-peak	f <sub>IN</sub> ≤ 2 GHz	0.5	1.35	V
	voltage	f <sub>IN</sub> = 125 MHz, 312.5 MHz		1.15	v
V <sub>AC_REF</sub>	Input bias voltage <sup>(2)</sup>	$I_{AC_{REF}} = 2 \text{ mA}$	V <sub>CC</sub> – 1.6	V <sub>CC</sub> – 1.1	V
	Propagation delay	$V_{IN, DIFF, PP} = 0.1V$		550	ps
t <sub>PD</sub>	Propagation delay	$V_{IN, DIFF, PP} = 0.3V$		550	ps
t <sub>SK,PP</sub>	Part-to-part skew			150	ps
t <sub>SK,O</sub>	Output skew			25	ps
t <sub>SK,P</sub>	Pulse skew (with 50% duty cycle input)	Crossing-point-to-crossing-point distortion, f <sub>OUT</sub> = 100 MHz	-50	50	ps

(1) Figure 10 and Figure 11 show dc and ac test setup.

(2) Internally generated bias voltage ( $V_{AC\_REF}$ ) is for 3.3 V operation only. It is recommended to apply externally generated bias voltage for  $V_{CC} < 3.0 V$ .

RUMENTS

AS

# Electrical Characteristics: LVPECL Output, At $V_{cc}$ = 2.375 V to 2.625 V<sup>(1)</sup> (continued)

 $T_A = -40^{\circ}C$  to +85°C (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
		$f_{OUT}$ = 100 MHz, $V_{IN,SE}$ = $V_{CC}$ , $V_{th}$ = 1.25 V, 10 kHz to 20 MHz	0.11		ps, RMS
		$f_{OUT}$ = 100 MHz, $V_{\text{IN,SE}}$ = 0.9 V, $V_{\text{th}}$ = 1.1 V, 10 kHz to 20 MHz	0.128		ps, RMS
		$      f_{OUT} = 2 \; GHz, \; V_{\text{IN,DIFF,PP}} = 0.2 \; \text{V}, \\ V_{\text{ICM}} = 1 \; \text{V}, \; 10 \; \text{kHz} \; \text{to} \; 20 \; \text{MHz} $	0.053		ps, RMS
		$      f_{OUT} = 100 \text{ MHz},  \text{V}_{\text{IN,DIFF,PP}} = 0.15 \text{ V}, \\ \text{V}_{\text{ICM}} = 1 \text{ V}, 10 \text{ kHz} \text{ to } 20 \text{ MHz} $	0.093		ps, RMS
		$      f_{OUT} = 100 \text{ MHz},  \text{V}_{\text{IN,DIFF,PP}} = 1 \text{ V}, \\ \text{V}_{\text{ICM}} = 1 \text{ V}, 10 \text{ kHz} \text{ to } 20 \text{ MHz} $	0.092		ps, RMS
		f <sub>OUT</sub> = 122.88 MHz, <sup>(4)(5)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 12 kHz to 20 MHz	0.057	0.088	ps, RMS
t <sub>rjit</sub>		f <sub>OUT</sub> = 122.88 MHz, <sup>(4)(5)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 10 kHz to 20 MHz	0.057	0.088	ps, RMS
	Random additive jitter (with 50% duty cycle input) <sup>(3)</sup>	f <sub>OUT</sub> = 122.88 MHz, <sup>(4)(5)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 1 kHz to 40 MHz	0.086	0.121	ps, RMS
		f <sub>OUT</sub> = 156.25 MHz, <sup>(5)(6)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 12 kHz to 20 MHz	0.048	0.071	ps, RMS
		f <sub>OUT</sub> = 156.25 MHz, <sup>(5)(6)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 10 kHz to 20 MHz	0.048	0.071	ps, RMS
		f <sub>OUT</sub> = 156.25 MHz, <sup>(5)(6)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 1 kHz to 40 MHz	0.068	0.097	ps, RMS
		f <sub>OUT</sub> = 312.5 MHz, <sup>(5)(7)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 12 kHz to 20 MHz	0.030	0.048	ps, RMS
		f <sub>OUT</sub> = 312.5 MHz, <sup>(5)(7)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 10 kHz to 20 MHz	0.030	0.048	ps, RMS
		f <sub>OUT</sub> = 312.5 MHz, <sup>(5)(7)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 1 kHz to 40 MHz	0.045	0.068	ps, RMS
t <sub>R</sub> /t <sub>F</sub>	Output rise/fall time	20% to 80%		200	ps
I <sub>EE</sub>	Supply internal current	Outputs unterminated		88	mA
I <sub>CC</sub>	Output and internal supply current	All outputs terminated, 50 $\Omega$ to V <sub>CC</sub> – 2		468	mA
-				-	

Parameter is specified by characterization. Not tested in production. (3)

(a) Input source: 122.88 MHz Rohde & Schwarz SMA100A Signal Generator.
(b) Input source RMS Jitter (t<sub>RJIT\_IN</sub>) and Total RMS Jitter (t<sub>RJIT\_OUT</sub>) measured using Agilent E5052 Phase Noise Analyzer. Buffer device random additive jitter computed as: t<sub>RJIT</sub> = SQRT[(t<sub>RJIT\_OUT</sub>)<sup>2</sup> - (t<sub>RJIT\_IN</sub>)<sup>2</sup>].
(c) Input source: 156.25 MHz Rohde & Schwarz SMA100A Signal Generator.
(d) Input source: 240 5 MHz Rohde & Schwarz SMA100A Signal Generator.

(7) Input source: 312.5 MHz Rohde & Schwarz SMA100A Signal Generator.



# 8.9 Electrical Characteristics: LVPECL Output, at $V_{CC}$ = 3.0 V to 3.6 V<sup>(1)</sup>

 $T_A = -40^{\circ}C$  to +85°C (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>OH</sub>	Output high voltage		V <sub>CC</sub> – 1.26		$V_{CC} - 0.9$	V
V <sub>OL</sub>	Output low voltage		V <sub>CC</sub> – 1.7		V <sub>CC</sub> - 1.3	V
V <sub>OUT, DIFF, PP</sub>	Differential output peak-peak voltage	f <sub>IN</sub> ≤ 2 GHz	0.65		1.35	V
V <sub>AC_REF</sub>	Input bias voltage	$I_{AC_{REF}} = 2 \text{ mA}$	V <sub>CC</sub> – 1.6		V <sub>CC</sub> – 1.1	V
	Dran a nation dalar	$V_{IN, DIFF, PP} = 0.1V$			550	ps
t <sub>PD</sub>	Propagation delay	$V_{IN, DIFF, PP} = 0.3V$			550	ps
t <sub>SK,PP</sub>	Part-to-part skew				150	ps
t <sub>SK,O</sub>	Output skew				25	ps
t <sub>SK,P</sub>	Pulse skew (with 50% duty cycle input)	Crossing-point-to-crossing-point distortion, $f_{OUT} = 100 \text{ MHz}$	-50		50	ps
		$f_{\text{OUT}} = 100 \text{ MHz},  \text{V}_{\text{IN,SE}} = \text{V}_{\text{CC}},  \text{V}_{\text{th}} = 1.65 \text{ V}, \\ 10 \text{ kHz} \text{ to } 20 \text{ MHz}$		0.101		ps, RMS
				0.130		ps, RMS
		$      f_{OUT} = 2 \; GHz, \; V_{\text{IN,DIFF,PP}} = 0.2 \; \text{V}, \\ V_{\text{ICM}} = 1 \; \text{V}, \; 10 \; \text{kHz} \; \text{to} \; 20 \; \text{MHz} $		0.069		ps, RMS
		$      f_{OUT} = 100 \text{ MHz},  \text{V}_{\text{IN,DIFF,PP}} = 0.15 \text{ V}, \\ \text{V}_{\text{ICM}} = 1 \text{ V}, 10 \text{ kHz} \text{ to } 20 \text{ MHz} $		0.094		ps, RMS
	Random additive jitter (with 50% duty cycle input) <sup>(2)</sup>	$f_{OUT} = 100 \text{ MHz}, V_{IN,DIFF,PP} = 1 \text{ V}, V_{ICM} = 1 \text{ V}, 10 \text{ kHz} \text{ to } 20 \text{ MHz}$		0.094		ps, RMS
		f <sub>OUT</sub> = 122.88 MHz, <sup>(3)(4)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 12 kHz to 20 MHz		0.057		ps, RMS
		f <sub>OUT</sub> = 122.88 MHz, <sup>(3)(4)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 10 kHz to 20 MHz		0.057		ps, RMS
t <sub>RJIT</sub>		f <sub>OUT</sub> = 122.88 MHz, <sup>(3)(4)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 1 kHz to 40 MHz		0.086		ps, RMS
	<i>,</i> , , ,	f <sub>OUT</sub> = 156.25 MHz, <sup>(4)(5)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 12 kHz to 20 MHz		0.048		ps, RMS
		f <sub>OUT</sub> = 156.25 MHz, <sup>(4)(5)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 10 kHz to 20 MHz		0.048		ps, RMS
		f <sub>OUT</sub> = 156.25 MHz, <sup>(4)(5)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 1 kHz to 40 MHz		0.068		ps, RMS
		f <sub>OUT</sub> = 312.5 MHz, <sup>(4)(6)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 12 kHz to 20 MHz		0.030		ps, RMS
		f <sub>OUT</sub> = 312.5 MHz, <sup>(4)(6)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 10 kHz to 20 MHz		0.030		ps, RMS
		f <sub>OUT</sub> = 312.5 MHz, <sup>(4)(6)</sup> Square Wave, V <sub>IN-PP</sub> = 1 V, 1 kHz to 40 MHz		0.045		ps, RMS
t <sub>R</sub> /t <sub>F</sub>	Output rise/fall time	20% to 80%			200	ps
I <sub>EE</sub>	Supply internal current	Outputs unterminated			88	mA
I <sub>CC</sub>	Output and internal supply current	All outputs terminated, 50 $\Omega$ to V <sub>CC</sub> – 2			468	mA

(1) Figure 10 and Figure 11 show dc and ac test setup.

(2)

(3)

Figure 10 and Figure 11 show dc and ac test setup. Parameter is specified by characterization. Not tested in production. Input source: 122.88 MHz Rohde & Schwarz SMA100A Signal Generator. Input source RMS Jitter ( $t_{RJIT_IN}$ ) and Total RMS Jitter ( $t_{RJIT_OUT}$ ) measured using Agilent E5052 Phase Noise Analyzer. Buffer device random additive jitter computed as:  $t_{RJIT} = SQRT[(t_{RJIT_OUT})^2 - (t_{RJIT_IN})^2]$ . Input source: 156.25 MHz Rohde & Schwarz SMA100A Signal Generator. Input source: 156.25 MHz Rohde & Schwarz SMA100A Signal Generator. (4)

(5)

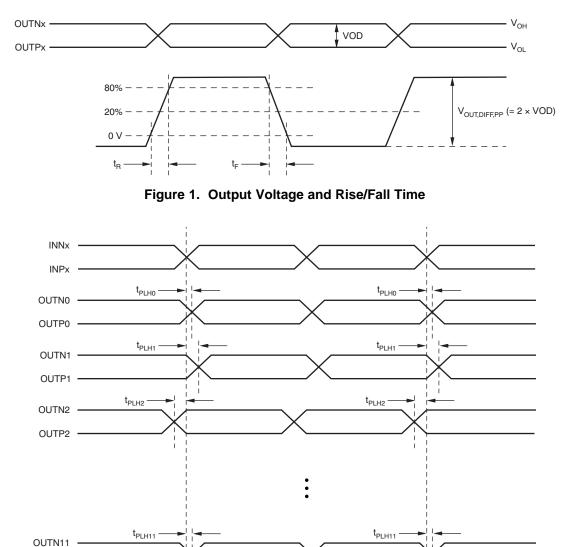
Input source: 312.5 MHz Rohde & Schwarz SMA100A Signal Generator. (6)

### CDCLVP1212

SCAS886D-AUGUST 2009-REVISED SEPTEMBER 2014

www.ti.com

## 8.10 Timing Requirements



- (2) Output skew is calculated as the greater of the following: As the difference between the fastest and the slowest t<sub>PLHn</sub> (n = 0, 1, 2....11), or as the difference between the fastest and the slowest t<sub>PHLn</sub> (n = 0, 1, 2....11).
- (3) Part-to-part skew is calculated as the greater of the following: As the difference between the fastest and the slowest t<sub>PLHn</sub> (n = 0, 1, 2....11) across multiple devices, or the difference between the fastest and the slowest t<sub>PHLn</sub> (n = 0, 1, 2....11) across multiple devices.

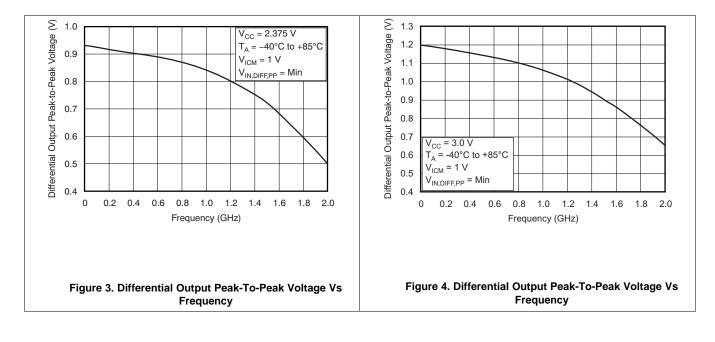
Figure 2. Output and Part-To-Part Skew

OUTP11



# 8.11 Typical Characteristics

At  $T_A = -40^{\circ}$ C to +85°C (unless otherwise noted).



### Texas Instruments

www.ti.com

# 9 Parameter Measurement Information

## 9.1 Test Configurations

This section describes the function of each block for the CDCLVP1212. Figure 6 through Figure 11 illustrate how the device should be set up for a variety of test configurations.

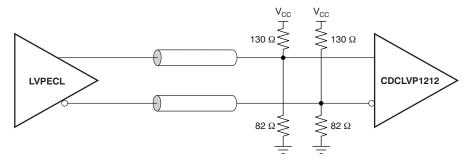


Figure 5. DC-Coupled LVPECL Input During Device Test

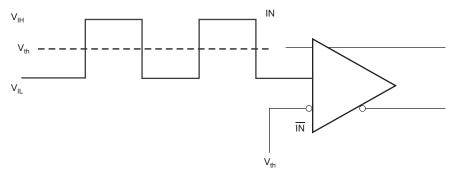


Figure 6. DC-Coupled LVCMOS Input During Device Test

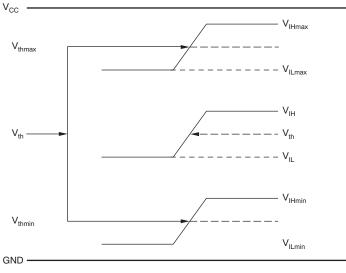


Figure 7. Voltage Variation Over LVCMOS V<sub>th</sub> Levels



# **Test Configurations (continued)**

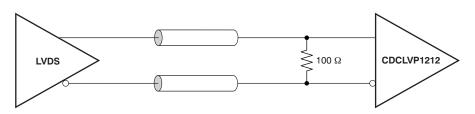


Figure 8. DC-Coupled LVDS Input During Device Test

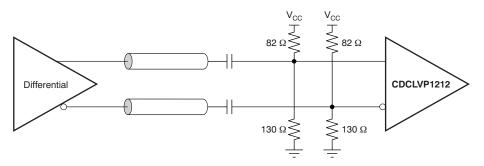


Figure 9. AC-Coupled Differential Input To Device

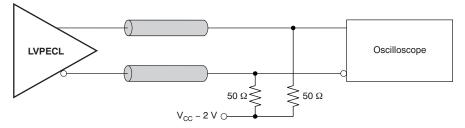


Figure 10. LVPECL Output DC Configuration During Device Test

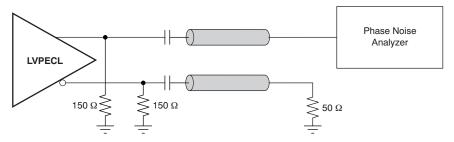


Figure 11. LVPECL Output AC Configuration During Device Test

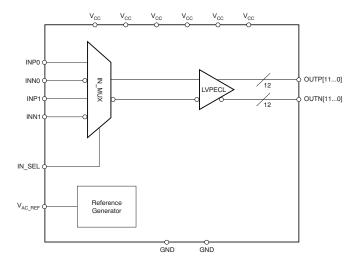


# **10 Detailed Description**

## 10.1 Overview

The CDCLVP1212 uses an open emitter follower stage for its LVPECL outputs. Therefore, proper output biasing and termination are required to ensure correct operation of the device and to maximize output signal integrity. The proper termination for LVPECL outputs is a 50  $\Omega$  to (VCC –2) V, but this dc voltage is not readily available on PCB. Therefore, a Thevenin equivalent circuit is worked out for the LVPECL termination in both direct-coupled (DC) and AC-coupled configurations. These configurations are shown in Figure 12 (a and b) for VCC = 2.5 V and Figure 13 (a and b) for VCC = 3.3 V, respectively. It is recommended to place all resistive components close to either the driver end or the receiver end. If the supply voltage for the driver and receiver is different, AC coupling is required.

# **10.2 Functional Block Diagram**



## **10.3 Feature Description**

The CDCLVP1212 is a low additive jitter universal to LVPECL fan out buffer with 2 selectable inputs. The small package, low output skew, and low additive jitter make for a flexible device in demanding applications.

# **10.4 Device Functional Modes**

The two inputs of the CDCLVP1212 are internally muxed together and can be selected via the control pin. Unused inputs and outputs can be left floating to reduce overall component cost. Both AC and DC coupling schemes can be used with the CDCLVP1212 to provide greater system flexibility.

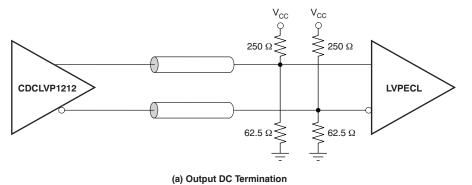
## 10.4.1 LVPECL Output Termination

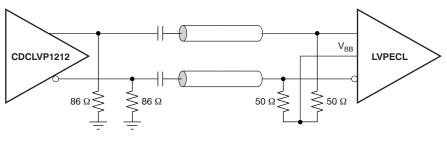
The CDCLVP1212 is an open emitter for LVPECL outputs. Therefore, proper biasing and termination are required to ensure correct operation of the device and to minimize signal integrity. The proper termination for LVPECL outputs is a 50  $\Omega$  to (V<sub>CC</sub> –2) V, but this dc voltage is not readily available on PCB. Therefore, a Thevenin equivalent circuit is worked out for the LVPECL termination in both direct-coupled (dc) and ac-coupled configurations. These configurations are shown in Figure 12 (a and b) for V<sub>CC</sub> = 2.5 V and Figure 13 (a and b) for V<sub>CC</sub> = 3.3 V, respectively. It is recommended to place all resistive components close to either the driver end or the receiver end. If the supply voltage for the driver and receiver is different, ac coupling is required.



### CDCLVP1212 SCAS886D – AUGUST 2009 – REVISED SEPTEMBER 2014

# **Device Functional Modes (continued)**



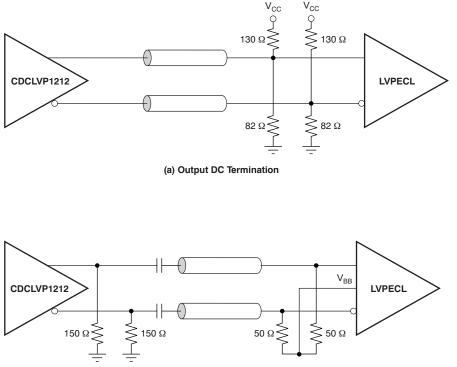


(b) Output AC Termination

Figure 12. LVPECL Output DC and AC Termination For  $V_{CC}$  = 2.5 V



## **Device Functional Modes (continued)**



(b) Output AC Termination

Figure 13. LVPECL Output DC and AC Termination For  $V_{CC}$  = 3.3 V

### 10.4.2 Input Termination

The CDCLVP1212 inputs can be interfaced with LVPECL, LVDS, or LVCMOS drivers. Figure 14 illustrates how to dc couple an LVCMOS input to the CDCLVP1212. The series resistance (R<sub>S</sub>) should be placed close to the LVCMOS driver; its value is calculated as the difference between the transmission line impedance and the driver output impedance.

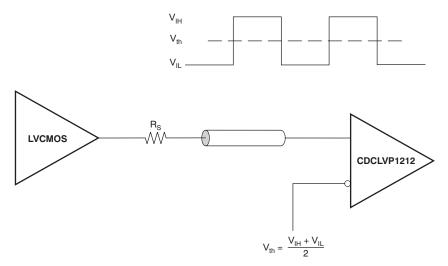


Figure 14. DC-Coupled LVCMOS Input to CDCLVP1212



### **Device Functional Modes (continued)**

Figure 15 shows how to dc couple LVDS inputs to the CDCLVP1212. Figure 16 and Figure 17 describe the method of dc coupling LVPECL inputs to the CDCLVP1212 for  $V_{CC} = 2.5$  V and  $V_{CC} = 3.3$  V, respectively.

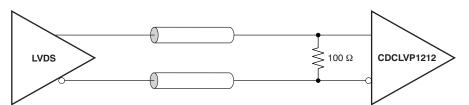


Figure 15. DC-Coupled LVDS Inputs to CDCLVP1212

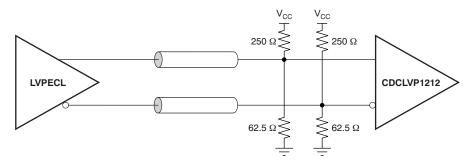


Figure 16. DC-Coupled LVPECL Inputs to CDCLVP1212 ( $V_{CC} = 2.5 V$ )

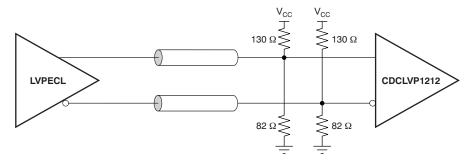


Figure 17. DC-Coupled LVPECL Inputs to CDCLVP1212 (V<sub>CC</sub> = 3.3 V)



## **Device Functional Modes (continued)**

Figure 18 and Figure 19 show the technique of ac coupling differential inputs to the CDCLVP1212 for  $V_{CC}$  = 2.5 V and  $V_{CC}$  = 3.3 V, respectively. It is recommended to place all resistive components close to either the driver end or the receiver end. If the supply voltages of the driver and receiver are different, ac coupling is required.

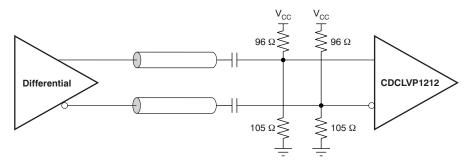


Figure 18. AC-Coupled Differential Inputs to CDCLVP1212 (V<sub>CC</sub> = 2.5 V)

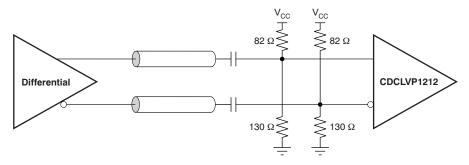


Figure 19. AC-Coupled Differential Inputs to CDCLVP1212 (V<sub>CC</sub> = 3.3 V)



# **11** Applications and Implementation

### NOTE

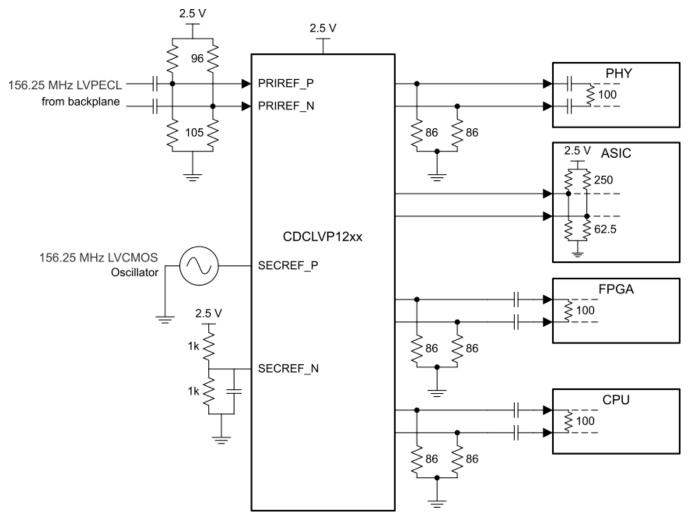
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

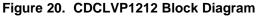
## **11.1** Application Information

The CDCLVP1212 is a low additive jitter LVPECL fanout buffer that can generate four copies of two selectable LVPECL, LVDS, or LVCMOS inputs. The CDCLVP1212 can accept reference clock frequencies up to 2 GHz while providing low output skew.

## **11.2 Typical Application**

## 11.2.1 Fanout Buffer for Line Card Application







## **Typical Application (continued)**

### 11.2.1.1 Design Requirements

The CDCLVP1212 shown in Figure 20 is configured to be able to select two inputs, a 156.25 MHz LVPECL clock from the backplane, or a secondary 156.25 MHz LVCMOS 2.5V oscillator. Either signal can be then fanned out to desired devices, as shown.

The configuration example is driving 4 LVPECL receivers in a line card application with the following properties:

- The PHY device has internal AC coupling and appropriate termination and biasing. The CDCLVP1212 will need to be provided with 86-Ω emitter resistors near the driver for proper operation.
- The ASIC is capable of DC coupling with a 2.5V LVPECL driver such as the CDCLVP1212. This ASIC features internal termination so no additional components are needed.
- The FPGA requires external AC coupling but has internal termination. Again, 86-Ω emitter resistors are placed near the CDCLVP1212 and 0.1 uF are placed to provide AC coupling. Similarly, the CPU is internally terminated and requires external AC coupling capacitors.

## 11.2.1.2 Detailed Design Procedure

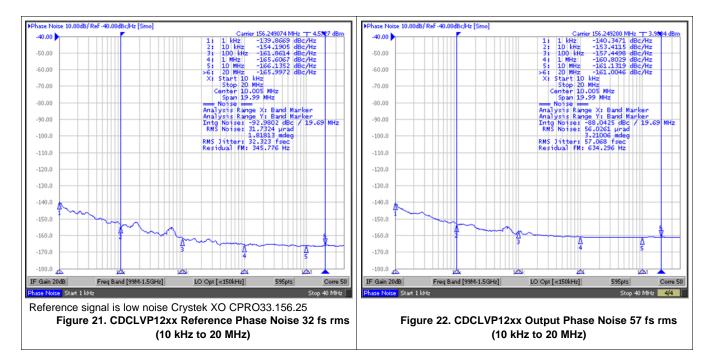
Refer to Input Termination for proper input terminations, dependent on single ended or differential inputs.

Refer to LVPECL Output Termination for output termination schemes depending on the receiver application.

Unused outputs can be left floating.

In this example, the PHY, ASIC, and FPGA/CPU require different schemes. Power supply filtering and bypassing is critical for low noise applications.

See *Power Supply Recommendations* for recommended filtering techniques. A reference layout is provided on the CDCLVP1212 Evaluation Module at SCAU036.



## 11.2.1.3 Application Curves

The CDCLVP12xx's low additive noise can be shown in this line card application. The low noise 156.25 MHz XO with 32 fs RMS jitter drives the CDCLVP12xx, resulting in 57 fs RMS when integrated from 10 kHz to 20 MHz. The resultant additive jitter is a low 47 fs RMS for this configuration.



# 12 Power Supply Recommendations

High-performance clock buffers are sensitive to noise on the power supply, which can dramatically increase the additive jitter of the buffer. Thus, it is essential to reduce noise from the system power supply, especially when jitter/phase noise is very critical to applications.

Filter capacitors are used to eliminate the low-frequency noise from the power supply, where the bypass capacitors provide the very low impedance path for high-frequency noise and guard the power-supply system against the induced fluctuations. These bypass capacitors also provide instantaneous current surges as required by the device and should have low equivalent series resistance (ESR). To properly use the bypass capacitors, they must be placed very close to the power-supply terminals and laid out with short loops to minimize inductance. It is recommended to add as many high-frequency (for example, 0.1  $\mu$ F) bypass capacitors as there are supply terminals in the package. It is recommended, but not required, to insert a ferrite bead between the board power supply and the chip power supply that isolates the high-frequency switching noises generated by the clock driver; these beads prevent the switching noise from leaking into the board supply. It is imperative to choose an appropriate ferrite bead with very low dc resistance in order to provide adequate isolation between the board supply and the chip supply, as well as to maintain a voltage at the supply terminals that is greater than the minimum voltage required for proper operation.

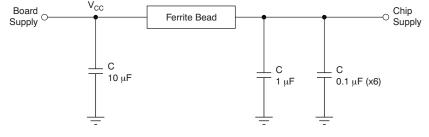


Figure 23 illustrates this recommended power-supply decoupling method.

Figure 23. Power-Supply Decoupling

## 12.1 Thermal Management

Power consumption of the CDCLVP1212 can be high enough to require attention to thermal management. For reliability and performance reasons, the die temperature should be limited to a maximum of +125°C. That is, as an estimate, ambient temperature ( $T_A$ ) plus device power consumption times  $R_{\theta JA}$  should not exceed +125°C.

The device package has an exposed pad that provides the primary heat removal path to the printed circuit board (PCB). To maximize the heat dissipation from the package, a thermal landing pattern including multiple vias to a ground plane must be incorporated into the PCB within the footprint of the package. The exposed pad must be soldered down to ensure adequate heat conduction out of the package. Figure 24 shows a recommended land and via pattern.

TEXAS INSTRUMENTS

www.ti.com

# 13 Layout

### 13.1 Layout Guidelines

Power consumption of the CDCLVP1212 can be high enough to require attention to thermal management. For reliability and performance reasons, the die temperature should be limited to a maximum of +125°C. That is, as an estimate, ambient temperature (TA) plus device power consumption times should not exceed +125°C.

The device package has an exposed pad that provides the primary heat removal path to the printed circuit board (PCB). To maximize the heat dissipation from the package, a thermal landing pattern including multiple vias to a ground plane must be incorporated into the PCB within the footprint of the package. The exposed pad must be soldered down to ensure adequate heat conduction out of the package. Figure 24 shows a recommended land and via pattern.

## 13.2 Layout Example

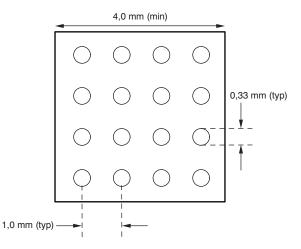


Figure 24. Recommended PCB Layout



# 14 Device and Documentation Support

### 14.1 Related Documentation

### 14.2 Trademarks

All trademarks are the property of their respective owners.

### 14.3 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

### 14.4 Glossary

### SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

## 15 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



5-Dec-2014

# PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
CDCLVP1212RHAR	ACTIVE	VQFN	RHA	40	2500	Green (RoHS & no Sb/Br)	CU	Level-3-260C-168 HR		CDCLVP 1212	Samples
CDCLVP1212RHAT	ACTIVE	VQFN	RHA	40	250	Green (RoHS & no Sb/Br)	CU	Level-3-260C-168 HR		CDCLVP 1212	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW**: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between

the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

<sup>(5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

<sup>(6)</sup> Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.



5-Dec-2014

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

# PACKAGE MATERIALS INFORMATION

www.ti.com

Texas Instruments

# TAPE AND REEL INFORMATION





# QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDCLVP1212RHAR	VQFN	RHA	40	2500	330.0	16.4	6.3	6.3	1.5	12.0	16.0	Q2
CDCLVP1212RHAT	VQFN	RHA	40	250	180.0	16.4	6.3	6.3	1.5	12.0	16.0	Q2

TEXAS INSTRUMENTS

www.ti.com

# PACKAGE MATERIALS INFORMATION

15-Sep-2014



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDCLVP1212RHAR	VQFN	RHA	40	2500	336.6	336.6	28.6
CDCLVP1212RHAT	VQFN	RHA	40	250	213.0	191.0	55.0

# **MECHANICAL DATA**



All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994. Α.

- Β. This drawing is subject to change without notice.
- QFN (Quad Flatpack No-Lead) Package configuration. C.
- The package thermal pad must be soldered to the board for thermal and mechanical performance. D.
- See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions. Ε.
- F. Package complies to JEDEC MO-220 variation VJJD-2.



#### **IMPORTANT NOTICE**

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

Products		Applications	
Audio	www.ti.com/audio	Automotive and Transportation	www.ti.com/automotive
Amplifiers	amplifier.ti.com	Communications and Telecom	www.ti.com/communications
Data Converters	dataconverter.ti.com	Computers and Peripherals	www.ti.com/computers
DLP® Products	www.dlp.com	Consumer Electronics	www.ti.com/consumer-apps
DSP	dsp.ti.com	Energy and Lighting	www.ti.com/energy
Clocks and Timers	www.ti.com/clocks	Industrial	www.ti.com/industrial
Interface	interface.ti.com	Medical	www.ti.com/medical
Logic	logic.ti.com	Security	www.ti.com/security
Power Mgmt	power.ti.com	Space, Avionics and Defense	www.ti.com/space-avionics-defense
Microcontrollers	microcontroller.ti.com	Video and Imaging	www.ti.com/video
RFID	www.ti-rfid.com		
OMAP Applications Processors	www.ti.com/omap	TI E2E Community	e2e.ti.com
Wireless Connectivity	www.ti.com/wirelessconne	ectivity	

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2014, Texas Instruments Incorporated



# Authorized Distribution Brand :



# Website :

Welcome to visit www.ameya360.com

# Contact Us :

➤ Address :

401 Building No.5, JiuGe Business Center, Lane 2301, Yishan Rd Minhang District, Shanghai , China

- > Sales :
  - Direct +86 (21) 6401-6692
  - Email amall@ameya360.com
  - QQ 800077892
  - Skype ameyasales1 ameyasales2

# > Customer Service :

Email service@ameya360.com

# > Partnership :

Tel +86 (21) 64016692-8333

Email mkt@ameya360.com